

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/517,040	WEISS ET AL.
Examiner	Art Unit	
	CUONG H. NGUYEN	3661

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
701	2,29	11/7/2008	CHN
700	17	11/7/2008	CHN
G05D 1/00,3/00		11/7/2008	CHN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
WEST/DERWENT frwd/bkwd searches on closest cited reference and allowable subject matter	11/7/2008	CHN
PG PUBS	11/7/2008	CHN
Inventors'names	11/7/2008	CHN
IEEE XPLORE	11/7/2008	CHN